

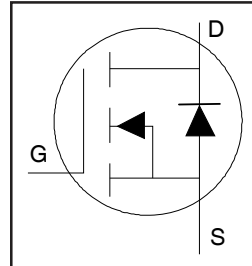
HEXFET® Power MOSFET

Applications

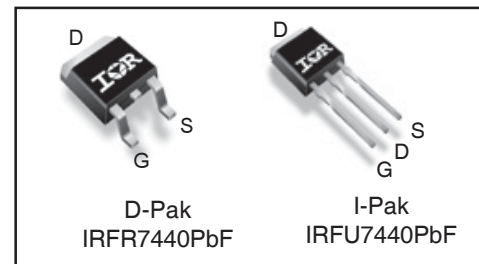
- Brushed Motor drive applications
- BLDC Motor drive applications
- PWM Inverterized topologies
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Electronic ballast applications
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free
- RoHS Compliant containing no Lead, no Bromide, and no Halogen



| | |
|-------------------------------|------------------------------|
| V_{DSS} | 40V |
| $R_{DS(on)}$ typ. max. | 1.9mΩ 2.4mΩ |
| I_D (Silicon Limited) | 180A ① |
| I_D (Package Limited) | 90A |



| | | |
|----------|----------|----------|
| G | D | S |
| Gate | Drain | Source |

| Base Part Number | Package Type | Standard Pack | | Orderable Part Number |
|------------------|--------------|---------------|----------|-----------------------|
| | | Form | Quantity | |
| IRFR7440PbF | D-PAK | Tube/Bulk | 75 | IRFR7440PbF |
| | | Tape and Reel | 2000 | IRFR7440TRPbF |
| IRFU7440PbF | I-PAK | Tube/Bulk | 75 | IRFU7440PbF |

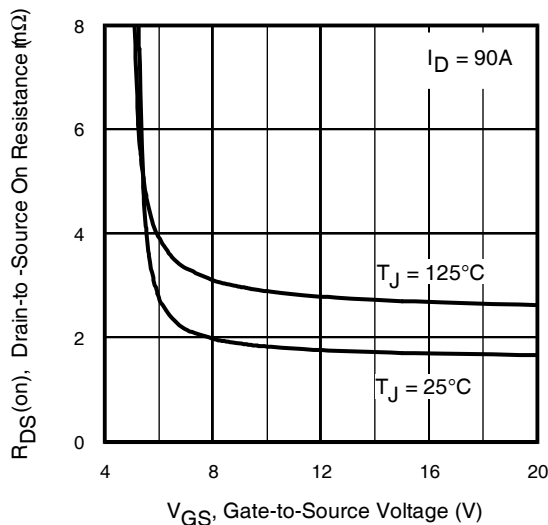


Fig 1. Typical On-Resistance vs. Gate Voltage

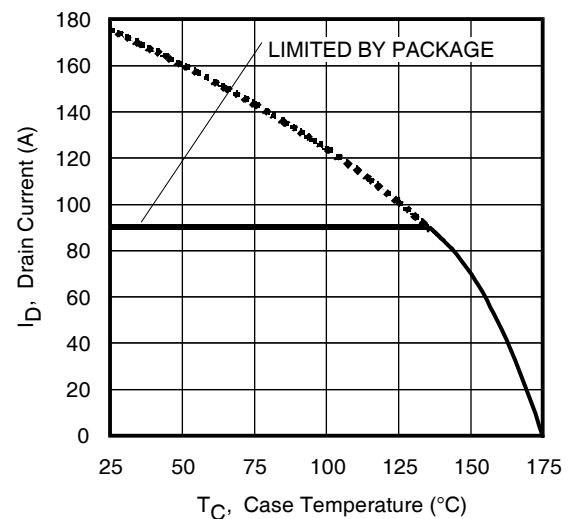


Fig 2. Maximum Drain Current vs. Case Temperature

Absolute Maximum Ratings

| Symbol | Parameter | Max. | Units |
|---------------------------------|---|------------------|-------|
| $I_D @ T_C = 25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10\text{V}$ (Silicon Limited) | 180 ^① | A |
| $I_D @ T_C = 100^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10\text{V}$ (Silicon Limited) | 125 ^① | |
| $I_D @ T_C = 25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10\text{V}$ (Wire Bond Limited) | 90 | |
| I_{DM} | Pulsed Drain Current ^② | 760 | |
| $P_D @ T_C = 25^\circ\text{C}$ | Maximum Power Dissipation | 140 | W |
| | Linear Derating Factor | 0.95 | W/°C |
| V_{GS} | Gate-to-Source Voltage | ± 20 | V |
| dv/dt | Peak Diode Recovery ^④ | 4.4 | V/ns |
| T_J | Operating Junction and | -55 to + 175 | °C |
| T_{STG} | Storage Temperature Range | | |
| | Soldering Temperature, for 10 seconds (1.6mm from case) | 300 | |

Avalanche Characteristics

| | | | |
|------------------------------|--|-------------------------|----|
| E_{AS} (Thermally limited) | Single Pulse Avalanche Energy ^③ | 160 | mJ |
| E_{AS} (Thermally limited) | Single Pulse Avalanche Energy ^⑩ | 376 | |
| I_{AR} | Avalanche Current ^② | See Fig 15,16, 23a, 23b | A |
| E_{AR} | Repetitive Avalanche Energy ^② | | mJ |

Thermal Resistance

| Symbol | Parameter | Typ. | Max. | Units |
|-----------------|--|------|------|-------|
| $R_{\theta JC}$ | Junction-to-Case ^⑨ | — | 1.05 | °C/W |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB Mount) ^⑨ | — | 50 | |
| $R_{\theta WA}$ | Junction-to-Ambient ^⑨ | — | 110 | |

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---------------------------------|--------------------------------------|------|------|------|-------|--|
| $V_{(BR)DSS}$ | Drain-to-Source Breakdown Voltage | 40 | — | — | V | $V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$ ^② |
| $\Delta V_{(BR)DSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient | — | 28 | — | mV/°C | Reference to 25°C , $I_D = 1\text{mA}$ |
| $R_{DS(on)}$ | Static Drain-to-Source On-Resistance | — | 1.9 | 2.4 | mΩ | $V_{GS} = 10\text{V}$, $I_D = 90\text{A}$ ^⑤ |
| | | — | 2.8 | — | mΩ | $V_{GS} = 6.0\text{V}$, $I_D = 50\text{A}$ ^⑤ |
| $V_{GS(th)}$ | Gate Threshold Voltage | 2.2 | 3.0 | 3.9 | V | $V_{DS} = V_{GS}$, $I_D = 100\mu\text{A}$ |
| I_{DSS} | Drain-to-Source Leakage Current | — | — | 1 | μA | $V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$ |
| | | — | — | 150 | | $V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 125^\circ\text{C}$ |
| I_{GSS} | Gate-to-Source Forward Leakage | — | — | 100 | nA | $V_{GS} = 20\text{V}$ |
| | Gate-to-Source Reverse Leakage | — | — | -100 | | $V_{GS} = -20\text{V}$ |
| R_G | Internal Gate Resistance | — | 2.6 | — | Ω | |

Notes:

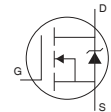
- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 90A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by T_{Jmax} , starting $T_J = 25^\circ\text{C}$, $L = 0.04\text{mH}$
 $R_G = 50\Omega$, $I_{AS} = 90\text{A}$, $V_{GS} = 10\text{V}$.
- ④ $I_{SD} \leq 100\text{A}$, $di/dt \leq 1306\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 175^\circ\text{C}$.
- ⑤ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑥ C_{OSS} eff. (TR) is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑦ C_{OSS} eff. (ER) is a fixed capacitance that gives the same energy as C_{OSS} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑧ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑨ R_{θ} is measured at T_J approximately 90°C .
- ⑩ Limited by T_{Jmax} starting $T_J = 25^\circ\text{C}$, $L = 1\text{mH}$, $R_G = 50\Omega$, $I_{AS} = 27\text{A}$, $V_{GS} = 10\text{V}$.

Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|----------------------------|---|------|------|------|-------|--|
| g_{fs} | Forward Transconductance | 280 | — | — | S | $V_{DS} = 10\text{V}$, $I_D = 90\text{A}$ |
| Q_g | Total Gate Charge | — | 89 | 134 | nC | $I_D = 90\text{A}$ $V_{DS} = 20\text{V}$ $V_{GS} = 10\text{V}$ ⑤ $I_D = 90\text{A}$, $V_{DS} = 0\text{V}$, $V_{GS} = 10\text{V}$ |
| Q_{gs} | Gate-to-Source Charge | — | 26 | — | | |
| Q_{gd} | Gate-to-Drain ("Miller") Charge | — | 26 | — | | |
| Q_{sync} | Total Gate Charge Sync. ($Q_g - Q_{gd}$) | — | 63 | — | | |
| $t_{d(on)}$ | Turn-On Delay Time | — | 11 | — | ns | |
| t_r | Rise Time | — | 39 | — | | $V_{DD} = 20\text{V}$ $I_D = 30\text{A}$ $R_G = 2.7\Omega$ $V_{GS} = 10\text{V}$ ⑤ |
| $t_{d(off)}$ | Turn-Off Delay Time | — | 51 | — | | |
| t_f | Fall Time | — | 34 | — | | |
| C_{iss} | Input Capacitance | — | 4610 | — | pF | |
| C_{oss} | Output Capacitance | — | 690 | — | | $V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{ MHz}$, See Fig. 5 $V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$ to 32V ⑦ See Fig. 12 $V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$ to 32V ⑥ |
| C_{rss} | Reverse Transfer Capacitance | — | 460 | — | | |
| $C_{oss\text{ eff. (ER)}}$ | Effective Output Capacitance (Energy Related) | — | 855 | — | | |
| $C_{oss\text{ eff. (TR)}}$ | Effective Output Capacitance (Time Related) | — | 1210 | — | | |

Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|-----------|---|------|------|------|-------|--|
| I_S | Continuous Source Current (Body Diode) | — | — | 180① | A | MOSFET symbol showing the integral reverse p-n junction diode. |
| I_{SM} | Pulsed Source Current (Body Diode) ② | — | — | 760 | A | |
| V_{SD} | Diode Forward Voltage | — | 0.9 | 1.3 | V | $T_J = 25^\circ\text{C}$, $I_S = 90\text{A}$, $V_{GS} = 0\text{V}$ |
| t_{rr} | Reverse Recovery Time | — | 34 | — | ns | $T_J = 25^\circ\text{C}$ $V_R = 34\text{V}$, $T_J = 125^\circ\text{C}$ $I_F = 90\text{A}$ $di/dt = 100\text{A}/\mu\text{s}$ ③ |
| Q_{rr} | Reverse Recovery Charge | — | 33 | — | nC | |
| | | — | 34 | — | | |
| I_{RRM} | Reverse Recovery Current | — | 1.8 | — | A | $T_J = 25^\circ\text{C}$ |



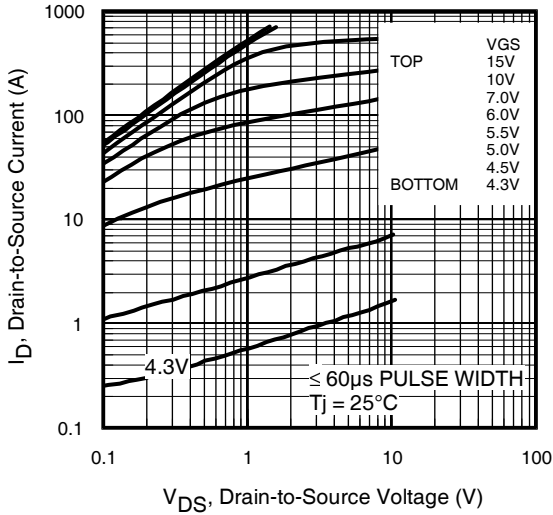


Fig 3. Typical Output Characteristics

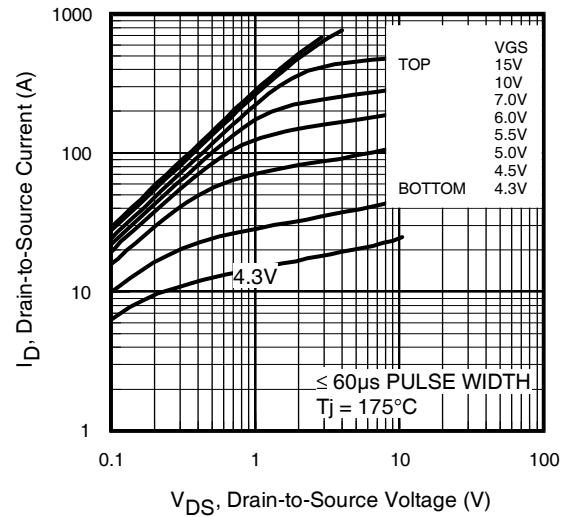


Fig 4. Typical Output Characteristics

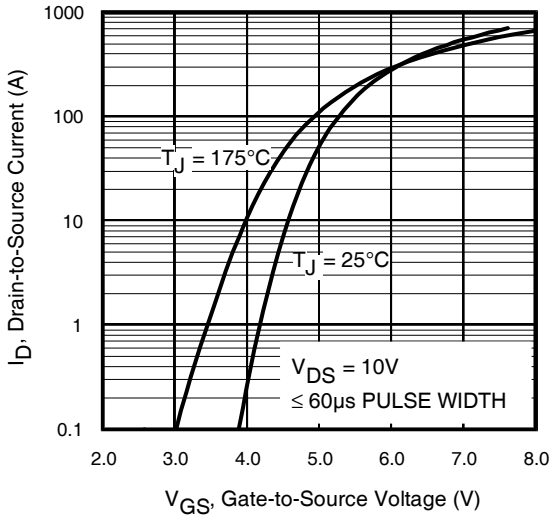


Fig 5. Typical Transfer Characteristics

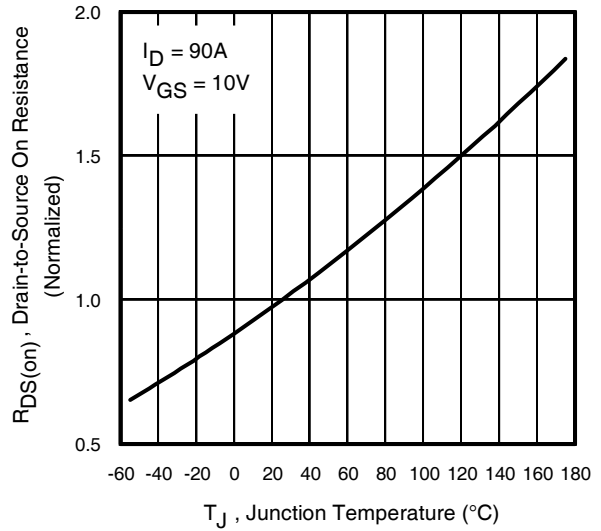


Fig 6. Normalized On-Resistance vs. Temperature

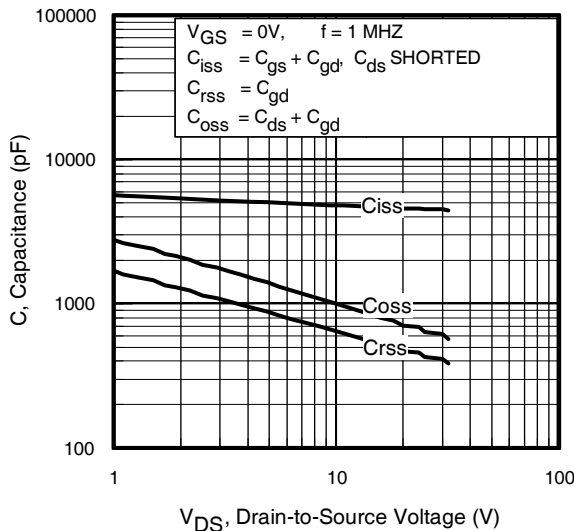


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

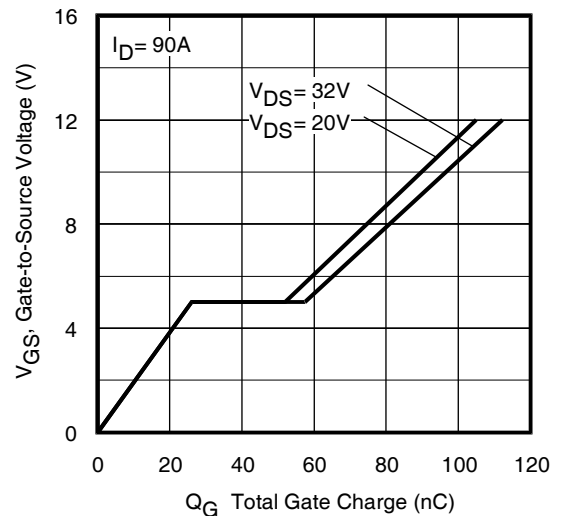


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage

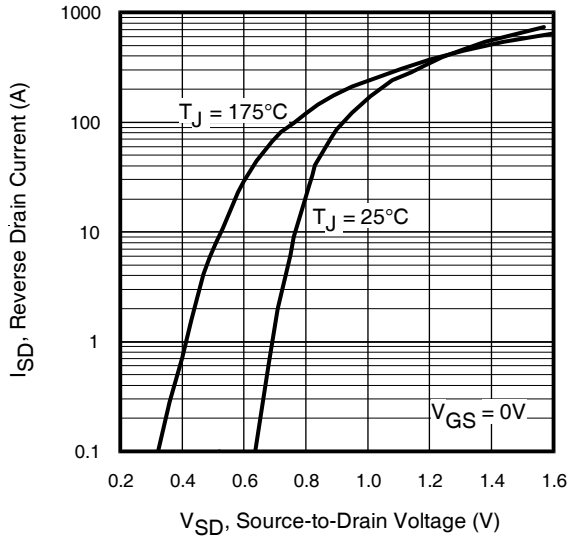


Fig 9. Typical Source-Drain Diode Forward Voltage

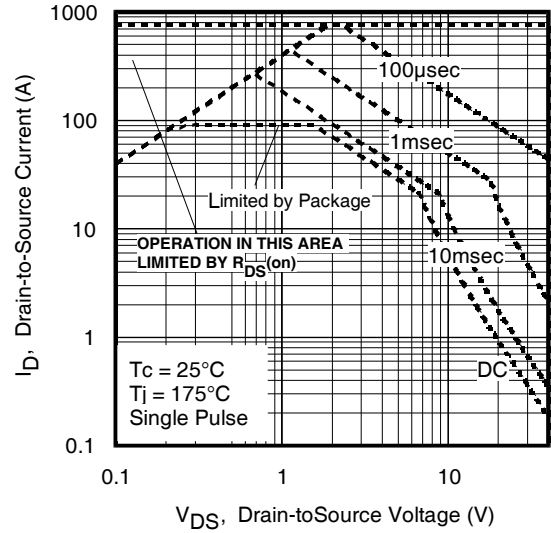


Fig 10. Maximum Safe Operating Area

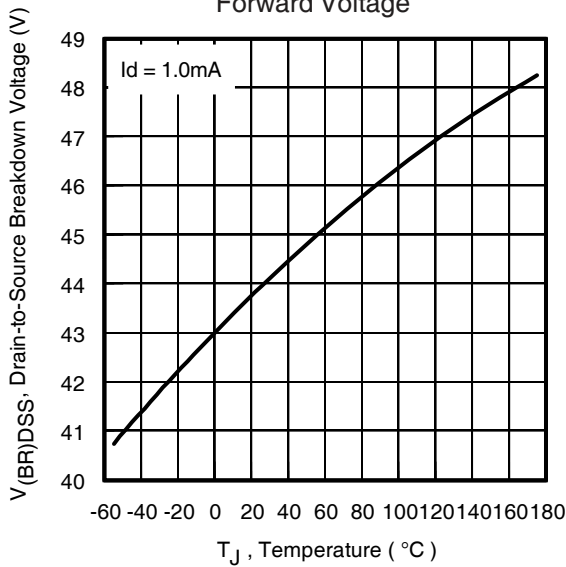


Fig 11. Drain-to-Source Breakdown Voltage

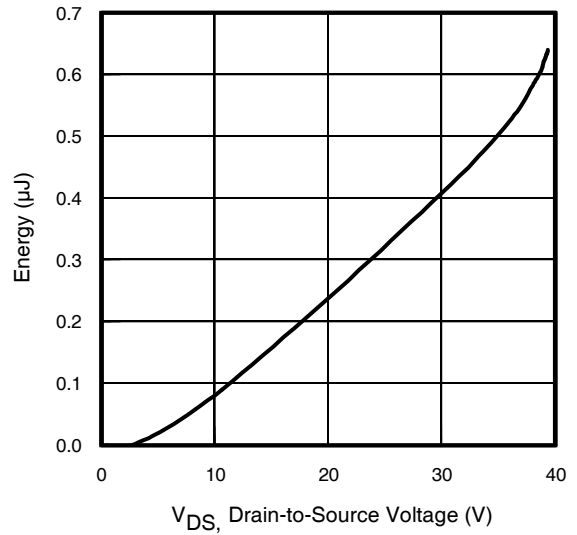


Fig 12. Typical C_{OSS} Stored Energy

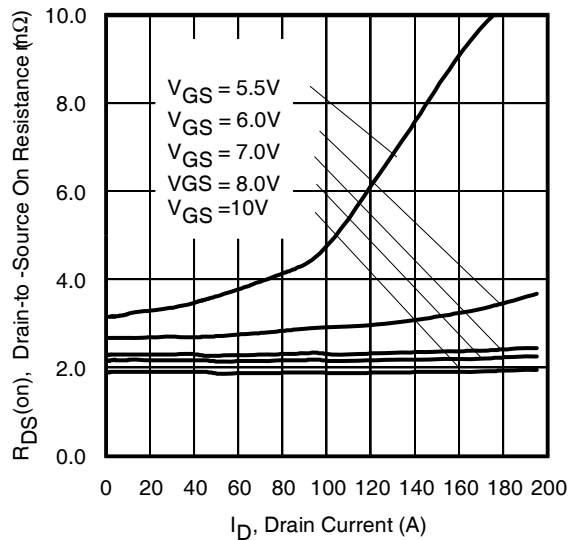


Fig 13. Typical On-Resistance vs. Drain Current

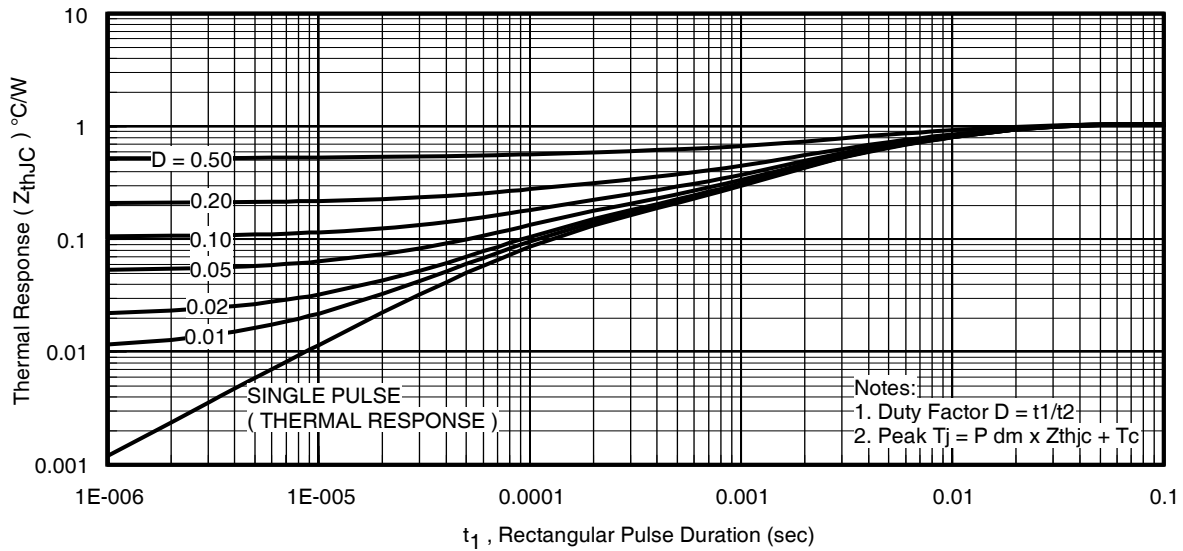


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

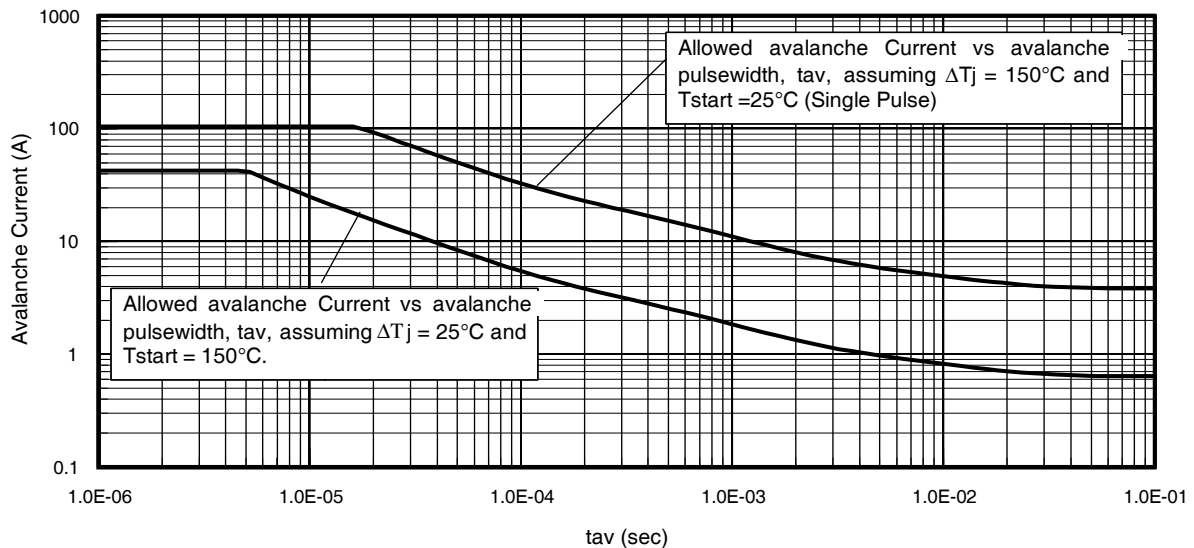


Fig 15. Typical Avalanche Current vs.Pulsewidth

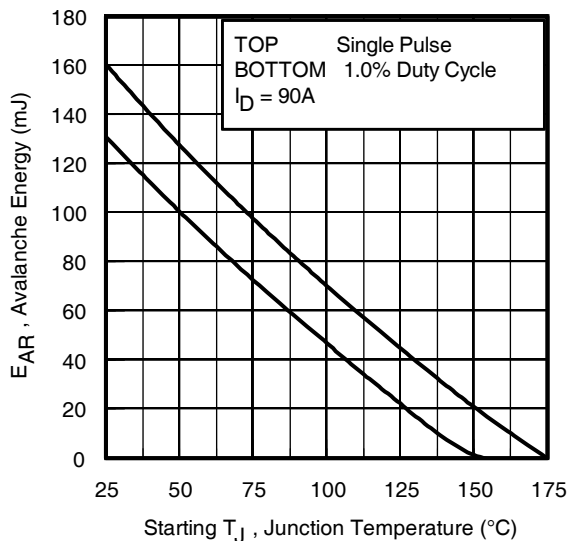


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
 t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 14)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

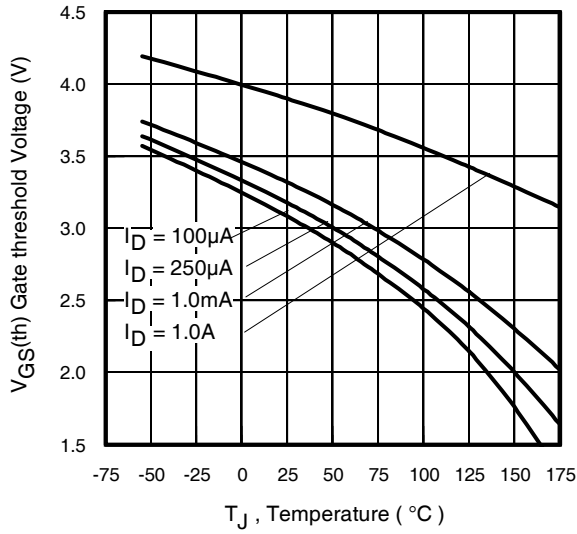


Fig 17. Threshold Voltage vs. Temperature

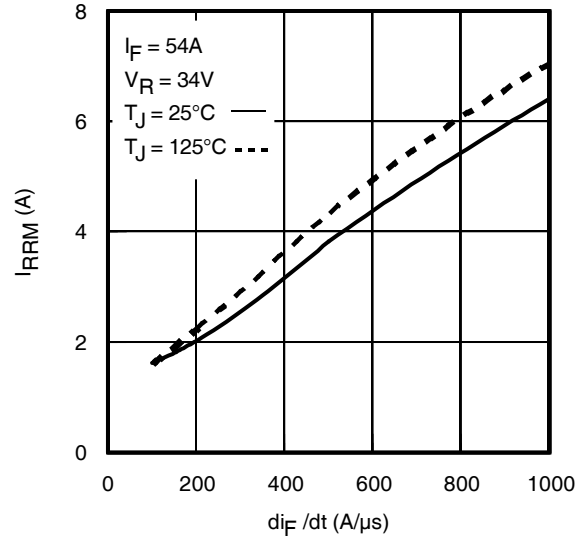


Fig. 18 - Typical Recovery Current vs. di_F/dt

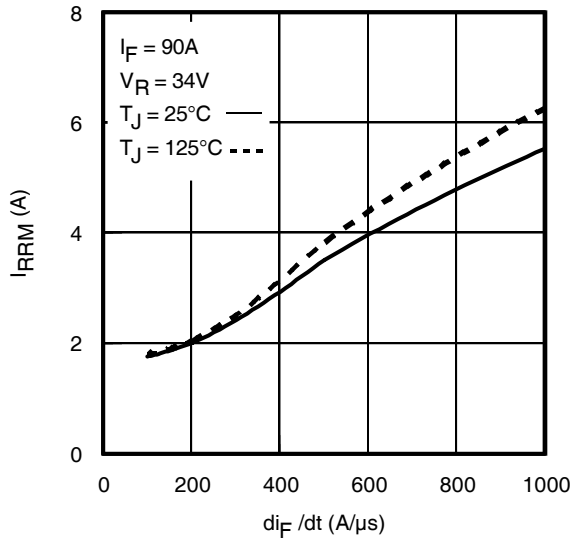


Fig. 19 - Typical Recovery Current vs. di_F/dt

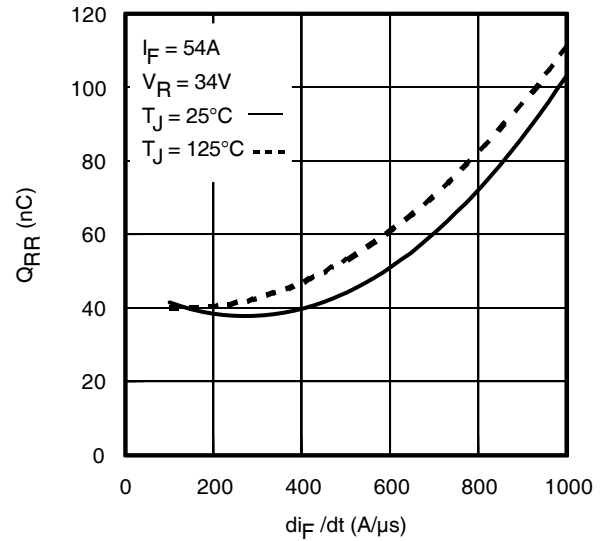


Fig. 20 - Typical Stored Charge vs. di_F/dt

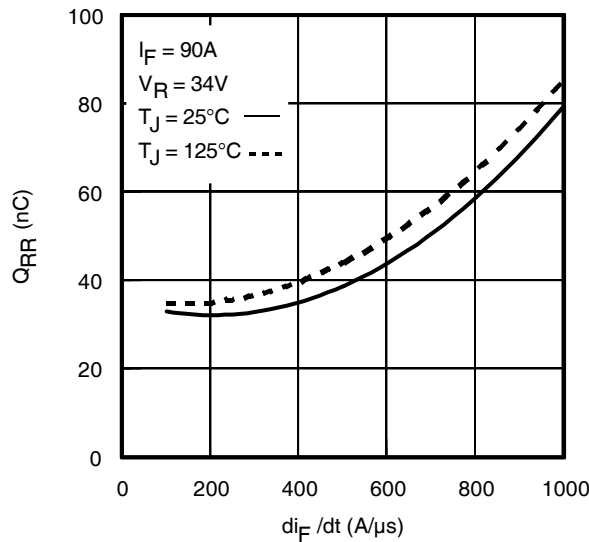
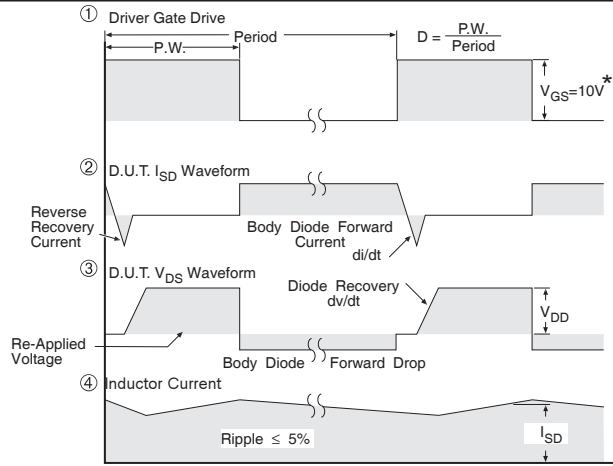
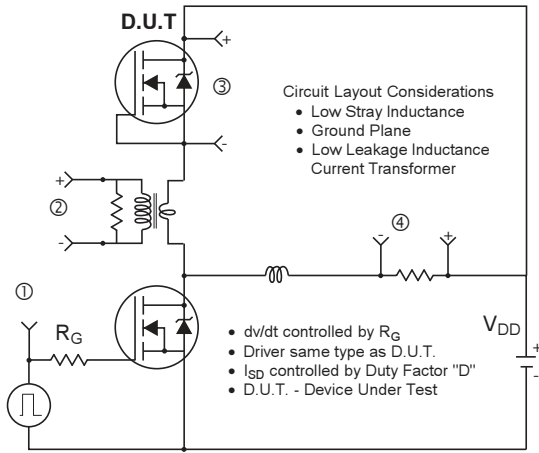


Fig. 21 - Typical Stored Charge vs. di_F/dt



* $V_{GS} = 5V$ for Logic Level Devices

Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

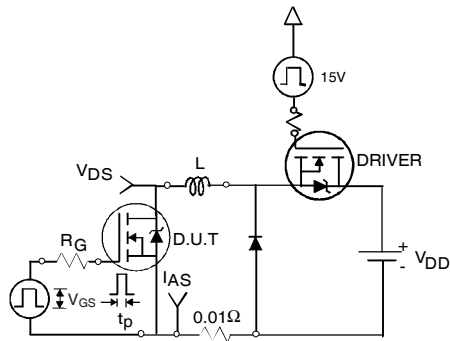


Fig 23a. Unclamped Inductive Test Circuit

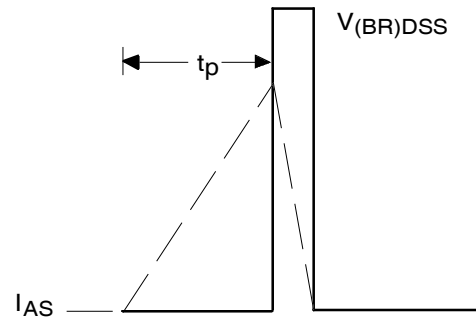


Fig 23b. Unclamped Inductive Waveforms

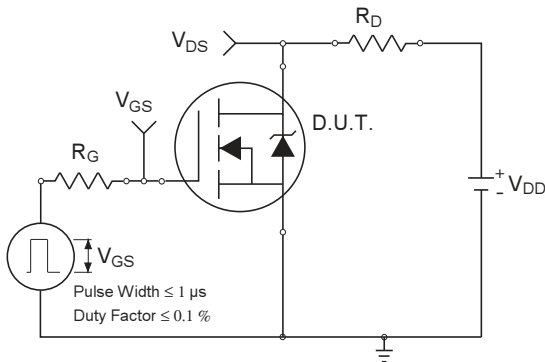


Fig 24a. Switching Time Test Circuit

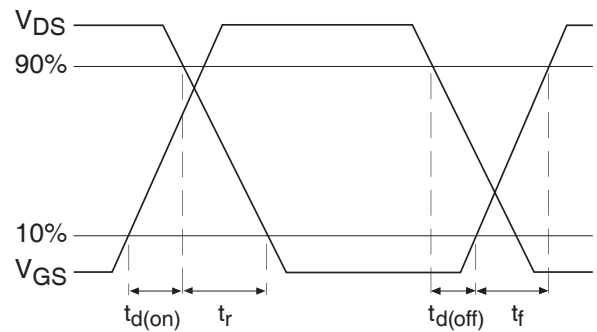


Fig 24b. Switching Time Waveforms

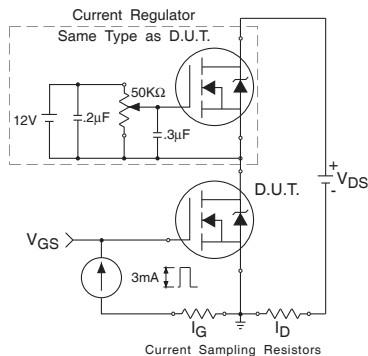


Fig 25a. Gate Charge Test Circuit

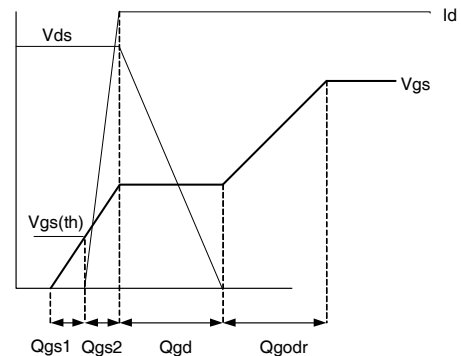
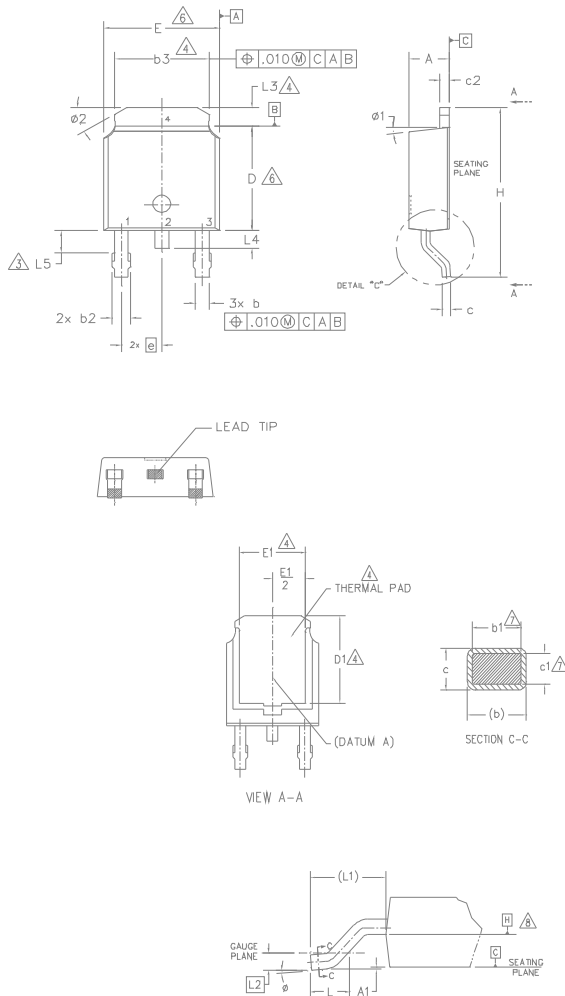


Fig 25b. Gate Charge Waveform

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- △ LEAD DIMENSION UNCONTROLLED IN L5.
- △ DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- △ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .006 [0.15] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- △ DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- △ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

| SYMBOL | DIMENSIONS | | | | NOTES |
|--------|-------------|-------|-----------|------|-------|
| | MILLIMETERS | | INCHES | | |
| | MIN. | MAX. | MIN. | MAX. | |
| A | 2.18 | 2.39 | .086 | .094 | |
| A1 | - | 0.13 | - | .005 | |
| b | 0.64 | 0.89 | .025 | .035 | |
| b1 | 0.64 | 0.79 | .025 | .031 | 7 |
| b2 | 0.76 | 1.14 | .030 | .045 | |
| b3 | 4.95 | 5.46 | .195 | .215 | 4 |
| c | 0.46 | 0.61 | .018 | .024 | |
| c1 | 0.41 | 0.56 | .016 | .022 | 7 |
| c2 | 0.46 | 0.89 | .018 | .035 | |
| D | 5.97 | 6.22 | .235 | .245 | 6 |
| D1 | 5.21 | - | .205 | - | 4 |
| E | 6.35 | 6.73 | .250 | .265 | 6 |
| E1 | 4.32 | - | .170 | - | 4 |
| e | 2.29 BSC | | .090 BSC | | |
| H | 9.40 | 10.41 | .370 | .410 | |
| L | 1.40 | 1.78 | .055 | .070 | |
| L1 | 2.74 BSC | | .108 REF. | | |
| L2 | 0.51 BSC | | .020 BSC | | |
| L3 | 0.89 | 1.27 | .035 | .050 | 4 |
| L4 | - | 1.02 | - | .040 | |
| L5 | 1.14 | 1.52 | .045 | .060 | 3 |
| φ | 0* | 10* | 0* | 10* | |
| φ1 | 0* | 15* | 0* | 15* | |
| φ2 | 25* | 35* | 25* | 35* | |

LEAD ASSIGNMENTS

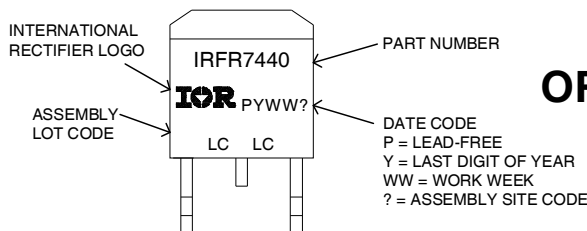
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

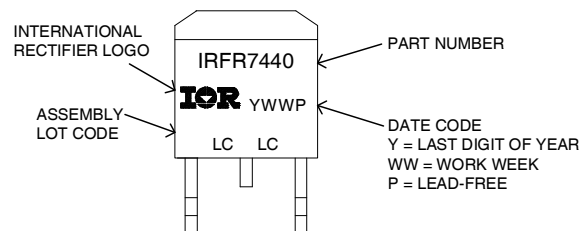
IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

D-Pak (TO-252AA) Part Marking Information



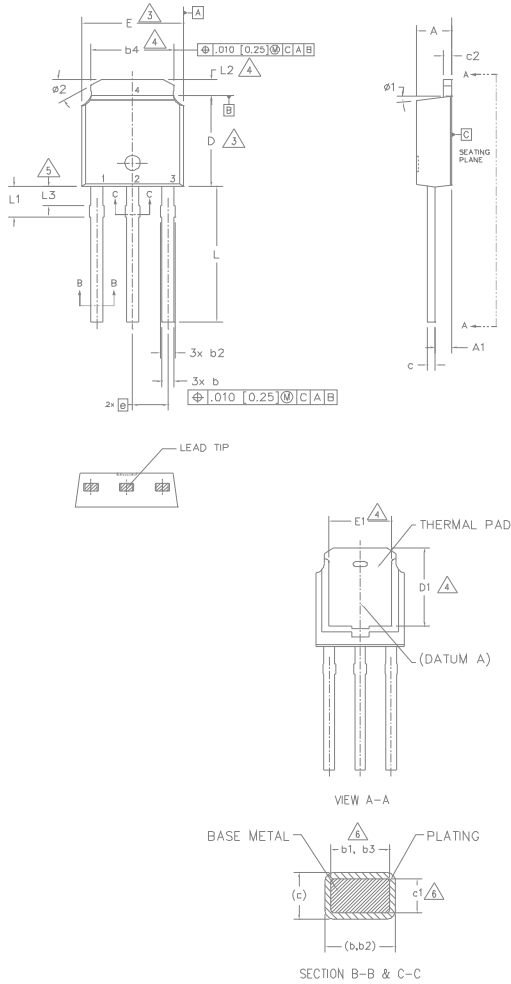
OR



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4.- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION b4, L2, E1 & D1.
- 5.- LEAD DIMENSION UNCONTROLLED IN L3.
- 6.- DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

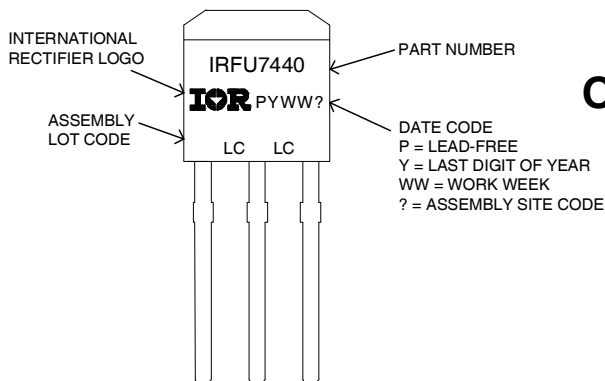
| SYMBOL | DIMENSIONS | | | | NOTES |
|--------|-------------|------|----------|------|-------|
| | MILLIMETERS | | INCHES | | |
| | MIN. | MAX. | MIN. | MAX. | |
| A | 2.18 | 2.39 | .086 | .094 | |
| A1 | 0.89 | 1.14 | .035 | .045 | |
| b | 0.64 | 0.89 | .025 | .035 | |
| b1 | 0.65 | 0.79 | .025 | .031 | 6 |
| b2 | 0.76 | 1.14 | .030 | .045 | |
| b3 | 0.76 | 1.04 | .030 | .041 | 6 |
| b4 | 4.95 | 5.46 | .195 | .215 | 4 |
| c | 0.46 | 0.61 | .018 | .024 | |
| c1 | 0.41 | 0.56 | .016 | .022 | 6 |
| c2 | 0.46 | 0.89 | .018 | .035 | |
| D | 5.97 | 6.22 | .235 | .245 | 3 |
| D1 | 5.21 | - | .205 | - | 4 |
| E | 6.35 | 6.73 | .250 | .265 | 3 |
| E1 | 4.32 | - | .170 | - | 4 |
| e | 2.29 BSC | | .090 BSC | | |
| L | 8.89 | 9.65 | .350 | .380 | |
| L1 | 1.91 | 2.29 | .045 | .090 | |
| L2 | 0.89 | 1.27 | .035 | .050 | 4 |
| L3 | 0.89 | 1.52 | .035 | .060 | 5 |
| Ø1 | 0" | 15" | 0" | 15" | |
| Ø2 | 25" | 35" | 25" | 35" | |

LEAD ASSIGNMENTS

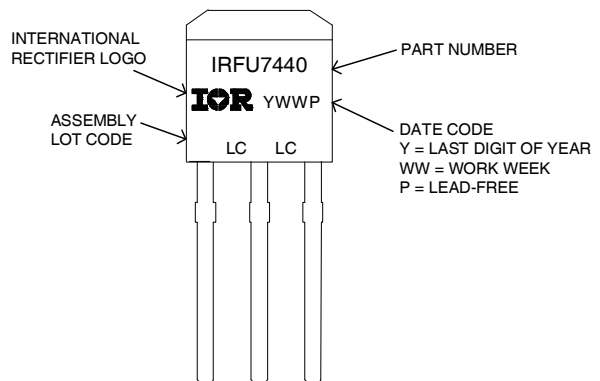
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

I-Pak (TO-251AA) Part Marking Information



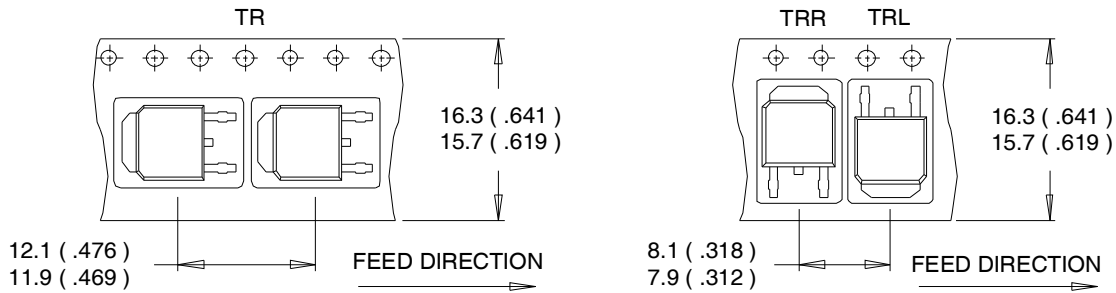
OR



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

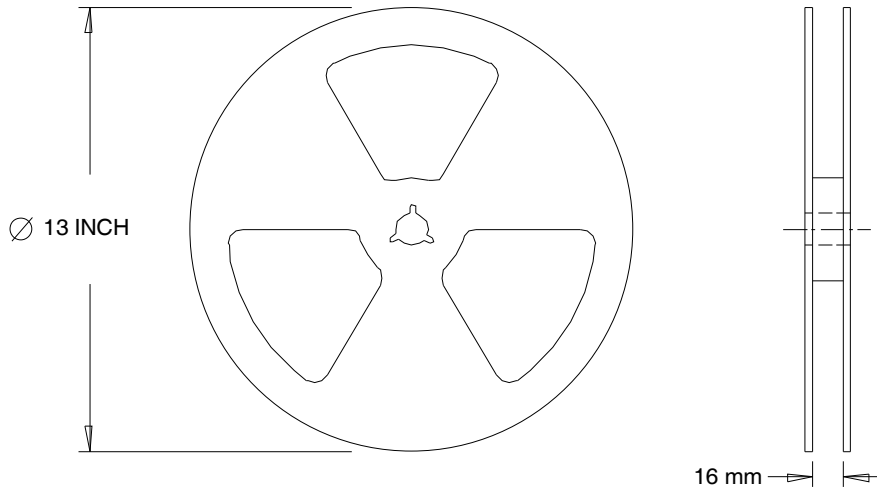
D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Qualification information[†]

| | | |
|----------------------------|---|--|
| Qualification level | Industrial ^{††} (per JEDEC JESD47F ^{†††} guidelines) | |
| Moisture Sensitivity Level | D-PAK | MSL1 (per JEDEC J-STD-020D ^{†††}) |
| | I-PAK | |
| RoHS compliant | Yes | |

† Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability/>

†† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: <http://www.irf.com/whoto-call/salesrep/>

††† Applicable version of JEDEC standard at the time of product release.

Revision History

| Date | Comments |
|------------|---|
| 10/17/2012 | <ul style="list-style-type: none"> Added I-Pak -All pages |
| 5/1/2014 | <ul style="list-style-type: none"> Updated data sheet based on corporate template. Added "Stong Fet" on header on page7. Updated package outline and part marking on page 9 & 10. |
| 1/6/2015 | <ul style="list-style-type: none"> Updated $E_{AS(L=1mH)} = 376mJ$ on page 2 Updated note 10 "Limited by T_{Jmax}, starting $T_J = 25^{\circ}C$, $L = 1mH$, $R_G = 50\Omega$, $I_{AS} = 27A$, $V_{GS} = 10V$". on page 2 |